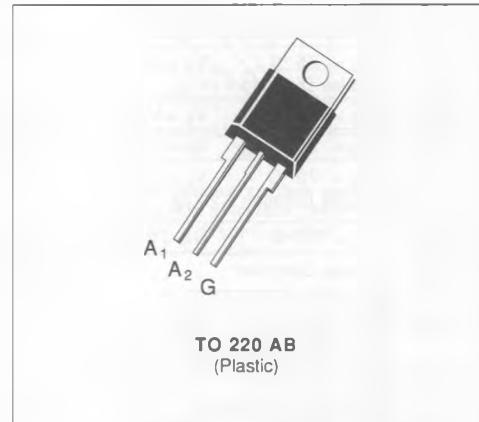


SENSITIVE GATE TRIACS

- GLASS PASSIVATED CHIP
- I_{GT} SPECIFIED IN FOUR QUADRANTS
- AVAILABLE IN INSULATED VERSION →
BTA SERIES (INSULATING VOLTAGE
2500 V_{RMS}) OR IN UNINSULATED VERSION
→ BTB SERIES
- UL RECOGNIZED FOR BTA SERIES (E81734)



DESCRIPTION

New range suited for applications such as phase control and static switching.

ABSOLUTE RATINGS (limiting values)

Symbol	Parameter	Value	Unit
$I_{T(RMS)}$	RMS on-state Current (360° conduction angle)	6	A
I_{TSR}	Non Repetitive Surge Peak on-state Current (T_j initial = 25 °C - Half sine wave)	t = 8.3 ms	A
		t = 10 ms	
I^2t	I^2t Value for Fusing	18	A ² s
di/dt	Critical Rate of Rise of on-state Current (1)	Repetitive $F = 50$ Hz	A/ μ s
		Non Repetitive	
T_{S1g} T_j	Storage and Operating Junction Temperature Range	- 40 to 150 - 40 to 110	°C °C

Symbol	Parameter	BTA/BTB 06-					Unit
		200A	400A	600A	700A	800A	
V_{DRM}	Repetitive Peak off-state Voltage (2)	200	400	600	700	800	V

(1) $I_G = 250$ mA $di/dt = 1$ A/ μ s

(2) $T_j = 110$ °C.

THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
$R_{th(j-a)}$	Junction to Ambient	60	°C/W
$R_{th(j-c)}$ DC	Junction to Case for DC	5.8	°C/W
$R_{th(j-c)}$ AC	Junction to Case for 360 ° Conduction Angle ($F = 50$ Hz)	4.3	°C/W

GATE CHARACTERISTICS (maximum values)

$$P_{GM} = 40 \text{ W } (t_p = 10 \mu\text{s}) \quad I_{GM} = 4 \text{ A } (t_p = 10 \mu\text{s})$$

$$P_G(\text{AV}) = 1 \text{ W} \quad V_{GM} = 16 \text{ V } (t_p = 10 \mu\text{s})$$

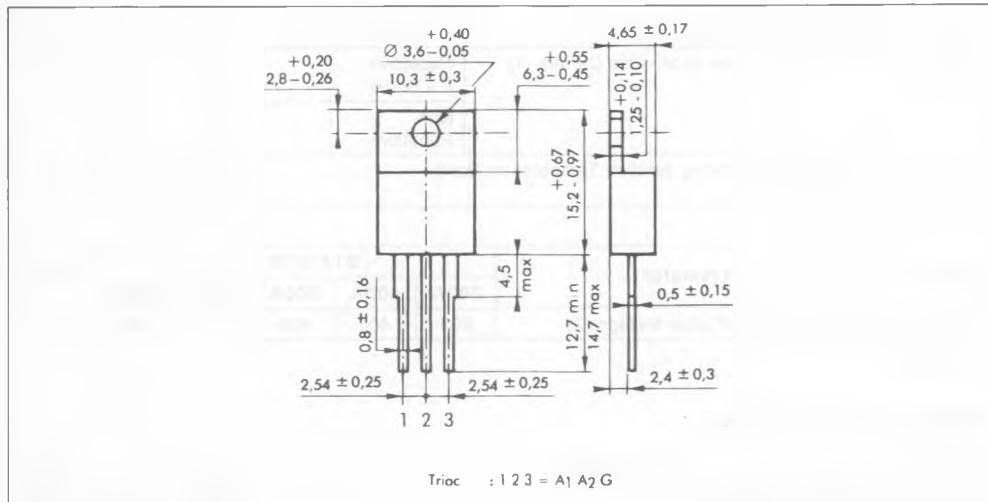
ELECTRICAL CHARACTERISTICS

Symbol	Test Conditions			Quadrants	Min.	Typ.	Max.	Unit
I_{GT}	$T_j = 25^\circ\text{C}$	$V_D = 12 \text{ V}$	$R_L = 33 \Omega$	I-II-III			10	mA
	Pulse Duration > 20 μs			IV			25	
V_{GT}	$T_j = 25^\circ\text{C}$	$V_D = 12 \text{ V}$	$R_L = 33 \Omega$	I-II-III-IV			1.5	V
V_{GD}	$T_j = 110^\circ\text{C}$	$V_D = V_{DRM}$	$R_L = 3.3 \text{ k}\Omega$	I-II-III-IV	0.2			V
I_H^*	$T_j = 25^\circ\text{C}$	$I_T = 100 \text{ mA}$	Gate Open				25	mA
I_L	$T_j = 25^\circ\text{C}$	$V_D = 12 \text{ V}$	$I_G = 50 \text{ mA}$	I-III-IV		25		mA
	Pulse Duration > 20 μs			II		50		
V_{TM}^*	$T_j = 25^\circ\text{C}$	$I_{TM} = 8.5 \text{ A}$	$t_p = 10 \text{ ms}$				1.65	V
I_{DRM}^*	V_{DRM} Specified		$T_j = 25^\circ\text{C}$				0.01	mA
			$T_j = 110^\circ\text{C}$				0.75	
dv/dt^*	$T_j = 110^\circ\text{C}$	Gate Open Linear Slope up to $V_D = 67\% V_{DRM}$			10			V/ μs
$(dv/dt)_c^*$	$T_C = 75^\circ\text{C}$	$V_D = V_{DRM}$	$I_T = 8.5 \text{ A}$			5		V/ μs
t_{g1}	$T_j = 25^\circ\text{C}$ $I_G = 40 \text{ mA}$	$V_D = V_{DRM}$	$I_T = 8.5 \text{ A}$	I-II-III-IV		2		μs

* For either polarity of electrode A₂ voltage with reference to electrode A₁.

PACKAGE MECHANICAL DATA

TO 220 AB Plastic



Cooling method : by conduction (method C)

Marking : type number

Weight : 2 g.

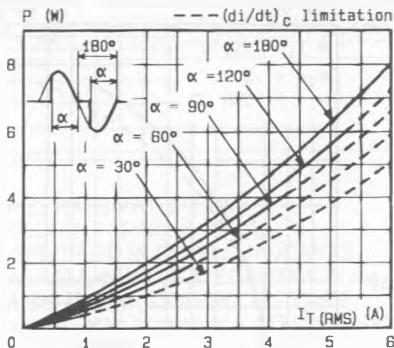


Fig.1 - Maximum mean power dissipation versus RMS on-state current ($f = 60$ Hz).

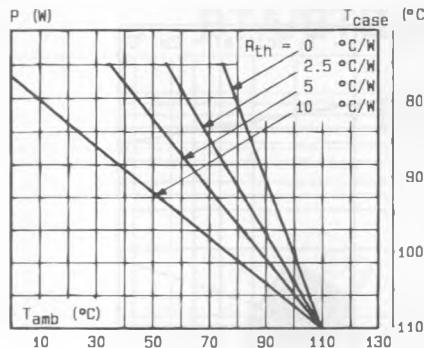


Fig.2 - Correlation between maximum mean power dissipation and maximum allowable temperatures (T_{amb} and T_{case}) for different thermal resistances heatsink + contact.

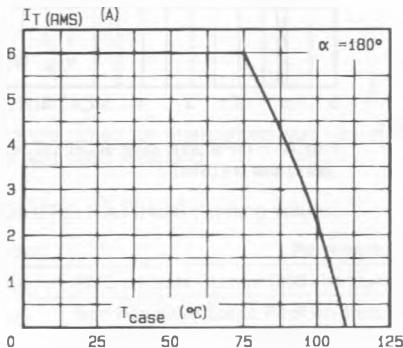


Fig.3 - RMS on-state current versus case temperature.

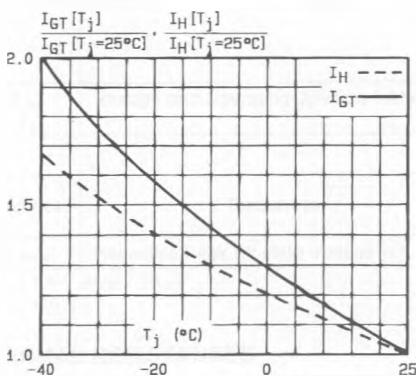


Fig.5 - Relative variation of gate trigger current and holding current versus junction temperature.

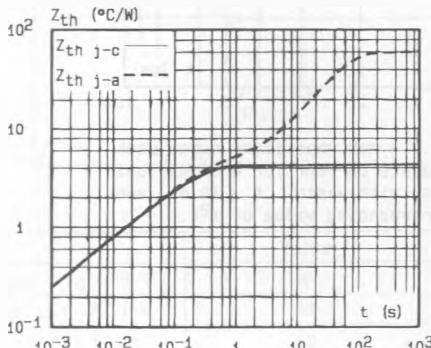


Fig.4 - Thermal transient impedance junction to case and junction to ambient versus pulse duration.

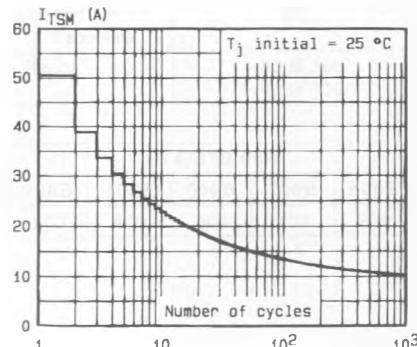


Fig.6 - Non repetitive surge peak on-state current versus number of cycles.

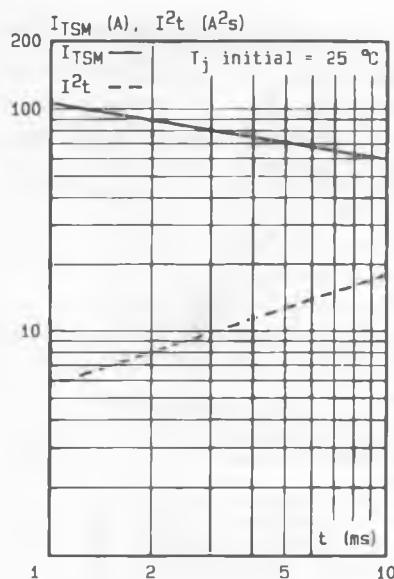


Fig.7 - Non repetitive surge peak on-state current for a sinusoidal pulse with width : $t \leq 10$ ms, and corresponding value of I^2t .

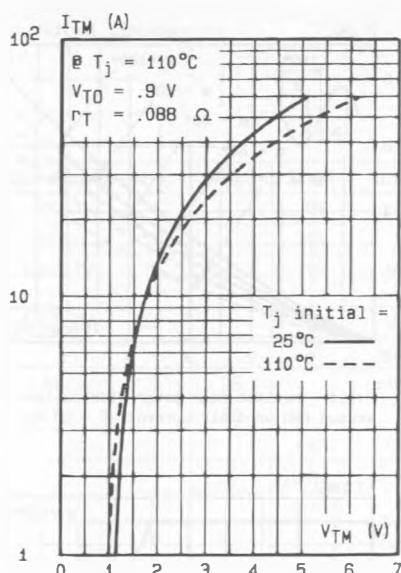


Fig.8 - On-state characteristics (maximum values).